

DEVICE TESTING CORRELATION TO ROOT CAUSE FAILURE ANALYSIS

ONLINE - NOV 4, 2010 • 11:00 A.M. EASTERN TIME

DEVICE TESTING CORRELATION TO ROOT CAUSE FAILURE ANALYSIS

Nov 4, 2010 • 11:00 a.m. Eastern Time • Course Length - One Hour.

Instructor: Leo G. Henry PhD, ESD TLP Consultants, LLC.

ESD Device Stress Testing is known to benefit at least three areas: qualifying the product, simulate failures from factory or field, and to improve the design of the product. Three ESD models (HBM, MM and CDM) are used to simulate failures and to differentiate between the different types of ESD failures and also to differentiate the ESD type failures from EOS-type failures. Even though there are no Failure Analysis standards for ESD, there is enough archived data, published data and experience to show correlation exists between the ESD Stress testing types, the physical failure types and the eventual root cause. The type of equipment required to get to the physical failures and see the failures will be emphasized. The class will show how to correlate each ESD model stress testing results to the physical failure type and the physical failure location on the die. A real example will be used to show how the ESD stress testing lead to the root cause of a field failure.

About the Instructor

Leo G. Henry is presently an ESD/TLP consulting engineer. He has worked in the electronics industry for over 26 years and in the field of ESD for over 20 years. Over the years, LeoG has worked in several engineering capacities/positions for several major companies having spent his first 14 "electronic" years at Advanced Micro Devices as a member of the Engineering Technical Staff.

Leo G. received both his B.Sc. and M.Sc. degrees in Physics with minors in chemistry and mathematics from the University of the West Indies. He received both his MS and Ph.D. degrees in Materials Science and Engineering from the University of California (UC Berkeley).

Dr. Henry has taught Physics at the University of West Indies, Mat. Sci. & FA Principles at SJ State University, and for the past 13 years, taught both EOS & ESD principles & testing at various Conferences and Symposiums including Silicon Valley's ESDiscovery, the ESD Symposium and ASM's ISTFA. Dr. Henry has presented at conferences and published (co-authored) many papers on ESD, EOS, TLP, FA and Materials Science. His technical expertise also includes system level testing using the IEC ESD standard, teaching several ESD classes in both the Program Manager and Device Design Certification disciplines, teaching at the University level and tutoring to high school students in Math, Physics and Chemistry.

Dr. Henry is a senior member of the IEEE, a member of ASM/EDFAS and BoD member of SiVa society. Leo G. is a member of WG-5.0 for Device Testing, serves on TPC, TAS, the ESDA's BoD. As Sr. VP of the ESDA, he has responsibility for Marketing & Communications, Human Resources, Facility Certification and the ESDA Head Quarters.

Equipment Requirements

This course uses a multi-way audio broadcast over the Internet. You will need a soundcard and speakers (a headset is recommended) installed to hear the presenter during the course.

Attendees can send questions to the presenter via text chat, other interaction is not available.

ESD Association • 7900 Turin Rd Bld 3 • Rome NY 13440
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ONLINE TRAINING

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Registration Form

First Name: _____ Last Name: _____

Company Name: _____

Street: _____ City: _____

State/Province: _____ Country _____ Zip/Postal Code: _____

Is Address (please circle the one that applies) Home or Company

Phone: _____ Fax: _____ Email: _____

Cost	members	non-members
	\$95.00	\$140.00

**Registration is requested by Oct 14th to guarantee course scheduling
Registrations will be accepted until Nov 3th**

Refunds will not be given for cancelations. In the event of a cancelation, credit will be given to attend a different online class.

Payment Information

Payment is required at time of registration. Only checks drawn in U.S. currency on a U.S. bank that is a member of the Federal Reserve will be accepted; make checks payable to ESD Association. Visa®, Mastercard®, Discover® and American Express® are accepted.

Amount enclosed \$ _____ Check Credit Card

Credit card type: Visa® Mastercard® Discover® American Express®

Credit card number: _____ Expiration date: _____

Name on card: _____ Security code: _____

Cardholder's signature: _____

Mail, or fax this form with payment to:

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